

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Shingo Saito

Confirmation No.: 5884

Serial No.: 10/561,280

Group Art Unit: 2886

Filed: 03/19/2007

Examiner: NGUYEN, TU T

Title: Optical Waveform Measurement Device and Measurement Method Thereof, Complex Refractive Index Measurement Device and Measurement Method Thereof, and Computer Program Recording Medium Containing the Program

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE AND AMENDMENT UNDER 37 CFR §1.121

Dear Sir:

This paper is filed in response to the Notice to File Corrected Application Papers mailed on June 21, 2010. A response is due by August 21, 2010. This response is being filed on or before August 21, 2010, therefore, this response is being timely filed.